

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 09/738,251 | Applicant(s)/Patent Under Reexamination HARDESTY ET AL. | |
| | Examiner Hien Tran | Art Unit 1764 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------------|----------------|
| | A | US-5,293,743 | 03-1994 | Usleman et al. | 60/299 |
| | B | US-5,555,621 | 09-1996 | Tanabe et al. | 29/890 |
| | C | US-6,555,070 | 04-2003 | Kruger, Klaus Gerhard | 422/179 |
| | D | US-6,605,259 | 08-2003 | Henry, Matthew Meredith | 422/179 |
| | E | US-6,635,227 | 10-2003 | Shibata et al. | 422/179 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|--------|----------------|
| | N | EP 992 659 | 04-2000 | EP | Kruger | --- |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.